

October 2013

ISL9V3036D3S / ISL9V3036S3S / ISL9V3036P3

EcoSPARK® 300mJ, 360V, N-Channel Ignition IGBT

General Description

The ISL9V3036D3S, ISL9V3036S3S, and ISL9V3036P3 are the next generation IGBTs that offer outstanding SCIS capability in the space saving D-Pak (TO-252), as well as the industry standard D²-Pak (TO-263) and TO-220 plastic packages. These devices are intended for use in automotive ignition circuits, specifically as a coil drivers. Internal diodes provide voltage clamping without the need for external components.

EcoSPARK® devices can be custom made to specific clamp voltages. Contact your nearest Fairchild sales office for more information.

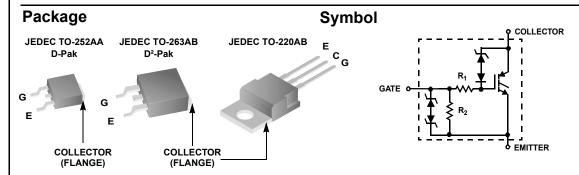
Formerly Developmental Type 49442

Applications

- · Automotive Ignition Coil Driver Circuits
- · Coil- On Plug Applications

Features

- Industry Standard D²-Pak package
- SCIS Energy = 300mJ at T_J = 25°C
- · Logic Level Gate Drive



Device Maximum Ratings T_{.I} = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
BV _{CER}	Collector to Emitter Breakdown Voltage (I _C = 1 mA)	360	V	
BV _{ECS}	Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA)	24	V	
E _{SCIS25}	$T_J = 25$ °C, $I_{SCIS} = 14.2A$, L = 3.0 mHy	300	mJ	
E _{SCIS150}	$T_J = 150$ °C, $I_{SCIS} = 10.6A$, L = 3.0 mHy	170	mJ	
I _{C25}	Collector Current Continuous, At T _C = 25°C, See Fig 9	21	Α	
I _{C110}	Collector Current Continuous, At T _C = 110°C, See Fig 9	17	Α	
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V	
P _D	Power Dissipation Total T _C = 25°C	150	W	
	Power Dissipation Derating T _C > 25°C	1.0	W/°C	
T _J	Operating Junction Temperature Range	-40 to 175	°C	
T _{STG}	Storage Junction Temperature Range	-40 to 175	°C	
T _L	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s) 300			
T _{pkg}	Max Lead Temp for Soldering (Package Body for 10s)	260	°C	
ESD	Electrostatic Discharge Voltage at 100pF, 1500 Ω			

V3036S ISL9V3036S3 TO_263AB 330mm 24mm 800 V3036P ISL9V3036P3 TO_220AA Tube N/A 50 V3036D ISL9V3036P3 TO_220AA Tube N/A 50 V3036D ISL9V3036P3 TO_263AB Tube N/A 50 V3036D ISL9V3036S3 TO_263AB Tube N/A 50 V3036S ISL9V3036S3 TO_263AB Tube N/A 50 V3036S ISL9V3036S3S TO_263AB Tube N/A 50 V3036S TO_263AB Tube N/A 50 Tube N/A 50 Tube Tube N/A 50 Tube Tube N/A 50 Tube Tube Tube Tube N/A 50 Tube Tub	evice Mark	ing	Device Package		Reel Size		Tape Width			Quantity	
V3036P					330mm					2500	
V3036D	V3036S		ISL9V3036S3ST	TO-263AB	330mm		24	lmm		800	
	V3036P		ISL9V3036P3 TO-220AA		Tube		N/A			50	
	V3036D		ISL9V3036D3S	TO-252AA	Tube		N/A			75	
	V3036S		ISL9V3036S3S	TO-263AB	Tube		١	N/A		50	
		I C			_		Min	Tun	May	I I mitte	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$		\		ei .	Test Con	uitions	IVIIII	тур	IVIAX	Units	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $				aledaven Valtaga	- 2m / \/	- o I	220	260	200		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	BVCER	Collector to Emitter Breakdown Voltage			$R_G = 1K\Omega$, See	330	300	390	V		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	BV _{CES}	Collector to Emitter Breakdown Voltage			$R_G = 0$, See Fig. 15		350	380	410	V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	BV _{ECS}	Emitt	er to Collector Brea	I _C = -75mA, V _{GE} = 0V,		30	-	-	V		
$ I_{ECS} Emitter to Collector Leakage Current R_G = 1K\Omega_k See Fig. 11 T_C = 150^{\circ}C - $	BV _{GES}	Gate	to Emitter Breakdo	own Voltage	$I_{GES} = \pm 2mA$		±12	±14	-	V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	I _{CER}	Colle	ctor to Emitter Lea	kage Current			-	-	25	μA	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$					See Fig. 11		-	-	1	mA	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	I _{ECS}	Emitt	er to Collector Lea			-	-	1	mA		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$					Fig. 11	$T_C = 150^{\circ}C$	-	-	40	mA	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		Series Gate Resistance					-		-	Ω	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$				nce			10K	-	26K	Ω	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	n State C	hara	acteristics								
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	V _{CE(SAT)}	Colle	ctor to Emitter Satu	uration Voltage			-	1.25	1.60	V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	V _{CE(SAT)}	Colle	ollector to Emitter Saturation Voltage				-	1.58	1.80	V	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	V _{CE(SAT)}	Colle	ctor to Emitter Satu		T _C = 150°C	-	1.90	2.20	V		
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	ynamic (har	acteristics								
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	-				I _C = 10A, V _{CE} = V _{GF} = 5V, See	= 12V, Fig. 14	-	17	-	nC	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	V _{GE(TH)}	Gate	to Emitter Thresho	old Voltage	I _C = 1.0mA,		1.3	-	2.2	V	
	()					T _C = 150°C	0.75	_	1.8	V	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	V_{GEP}	Gate to Emitter Plateau Voltage			I _C = 10A,	V _{CE} = 12V	-	3.0	-	V	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	witching	Cha	racteristics								
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{d(ON)R}	Current Turn-On Delay Time-Resistive			$V_{CE} = 14V, R_{L} = 1\Omega,$		-	0.7	4	μs	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		Curre	ent Rise Time-Resi			-	2.1	7	μs		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{d(OFF)L}	Curre	ent Turn-Off Delay	Time-Inductive			-	4.8	15	μs	
$R_G = 1K\Omega$, $V_{GE} = 5V$	t _{fL}				T_J = 25°C, See Fig. 12		-	2.8	15	μs	
hormal Characteristics	SCIS	Self	Clamped Inductive	Switching			-	-	300	mJ	
Herrial Characteristics											

Typical Performance Curves

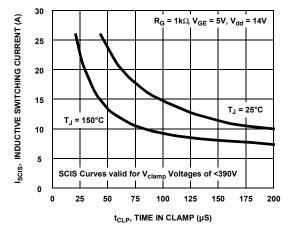


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

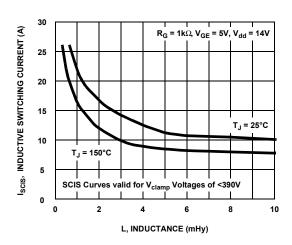


Figure 2. Self Clamped Inductive Switching Current vs Inductance

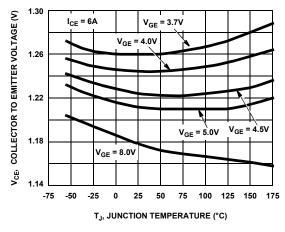


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

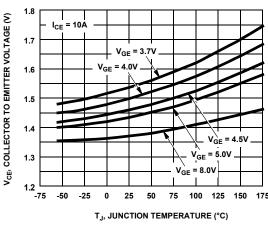


Figure 4. Collector to Emitter On-State Voltage vs Junction Temperature

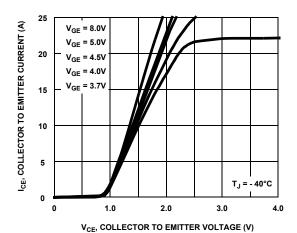


Figure 5. Collector to Emitter On-State Voltage vs Collector Current

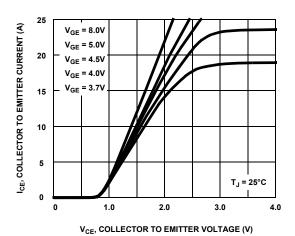


Figure 6. Collector to Emitter On-State Voltage vs Collector Current

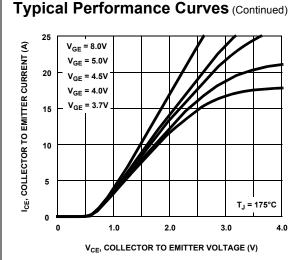


Figure 7. Collector to Emitter On-State Voltage vs Collector Current

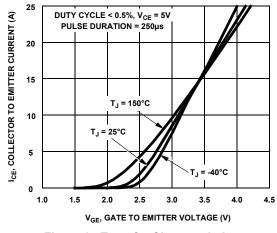


Figure 8. Transfer Characteristics

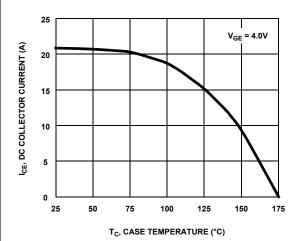


Figure 9. DC Collector Current vs Case Temperature

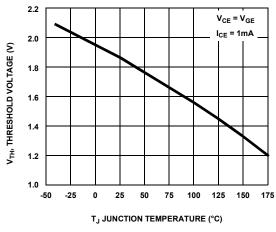


Figure 10. Threshold Voltage vs Junction Temperature

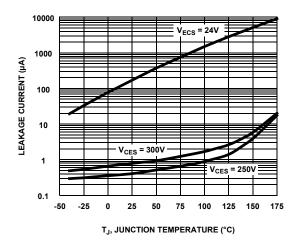


Figure 11. Leakage Current vs Junction Temperature

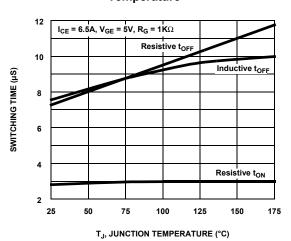
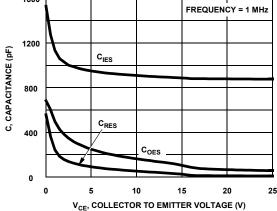


Figure 12. Switching Time vs Junction Temperature

Typical Performance Curves (Continued) FREQUENCY = 1 MHz 1200



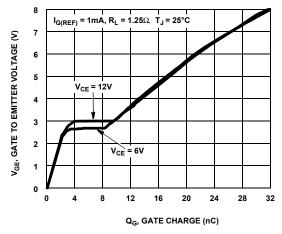


Figure 13. Capacitance vs Collector to Emitter Voltage

Figure 14. Gate Charge

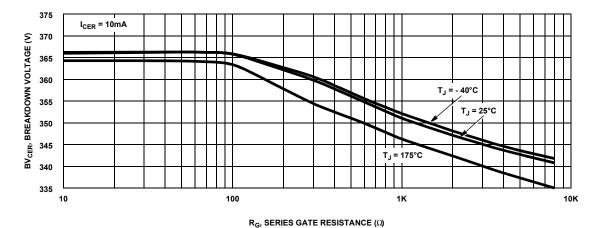


Figure 15. Breakdown Voltage vs Series Gate Resistance

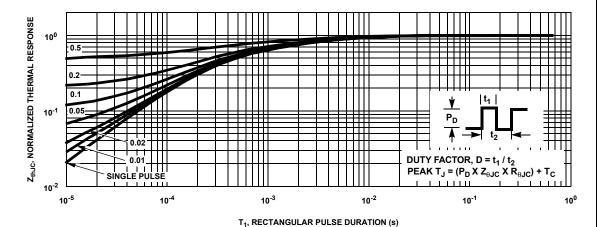
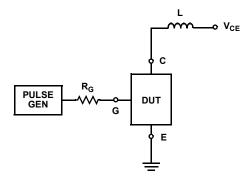


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

Test Circuit and Waveforms



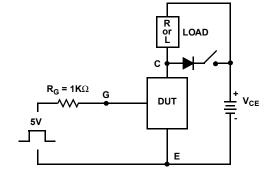


Figure 17. Inductive Switching Test Circuit

Figure 18. $t_{\rm ON}$ and $t_{\rm OFF}$ Switching Test Circuit

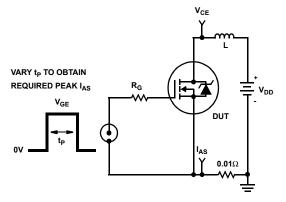


Figure 19. Unclamped Energy Test Circuit

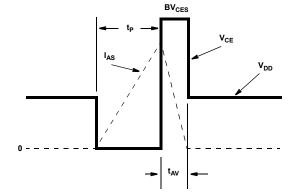


Figure 20. Unclamped Energy Waveforms

SPICE Thermal Model JUNCTION **REV 24 April 2002** ISL9V3036D3S/ ISL9V3036S3S / ISL9V3036P3 CTHERM1 th 6 2.1e -3 CTHERM2 6 5 1.4e -1 RTHERM1 CTHERM1 CTHERM3 5 4 7.3e -3 CTHERM4 4 3 2.1e -1 CTHERM5 3 2 1.1e -1 CTHERM6 2 tl 6.2e +6 6 RTHERM1 th 6 1.2e -1 RTHERM2 6 5 1.9e -1 RTHERM2 CTHERM2 RTHERM3 5 4 2.2e -1 RTHERM4 4 3 6.0e -2 RTHERM5 3 2 5.8e -2 RTHERM6 2 tl 1.6e -3 5 SABER Thermal Model RTHERM3 CTHERM3 SABER thermal model ISL9V3036D3S / ISL9V3036S3S / ISL9V3036P3 template thermal_model th tl thermal_c th, tl ctherm.ctherm1 th 6 = 2.1e - 3ctherm.ctherm2 6 5 = 1.4e -1 ctherm.ctherm3 5 4 = 7.3e -3 RTHERM4 CTHERM4 ctherm.ctherm4 4 3 = 2.2e -1 ctherm.ctherm5 3 2 =1.1e -1 ctherm.ctherm6 2 tl = 6.2e +6 3 rtherm.rtherm1 th 6 = 1.2e -1 rtherm.rtherm2 6 5 = 1.9e -1 rtherm.rtherm3 5 4 = 2.2e -1 RTHERM5 CTHERM5 rtherm.rtherm4 4 3 = 6.0e -2 rtherm.rtherm5 3 2 = 5.8e -2 rtherm.rtherm6 2 tl = 1.6e -3 2 RTHERM6 CTHERM6 CASE





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Definition of Torms

Deminition of Terms		
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Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
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